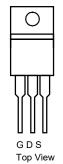


ROHS COMPLIANT

## IRFB7446GPBF-VB Datasheet N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY		
V <sub>DS</sub>	40	V
R <sub>DS(on)</sub> V <sub>GS</sub> = 10 V	2	mΩ
ID	180	А
Configuration	Sin	gle



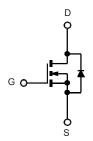


### FEATURES

- Trench Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested

#### **APPLICATIONS**

- Synchronous Rectification
- Power Supplies



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T Parameter	<u>A</u> ,	Symbol	Limit	Unit
Drain-Source Voltage		V <sub>DS</sub>	40	
Gate-Source Voltage		V <sub>GS</sub>	± 20	V
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>C</sub> = 25 °C		180 <sup>a, c</sup>	
	T <sub>C</sub> = 70 °C		150°	
	T <sub>A</sub> = 25 °C	I <sub>D</sub>	29 <sup>b</sup>	A
	T <sub>A</sub> = 70 °C		23 <sup>b</sup>	— A
Pulsed Drain Current		I <sub>DM</sub>	350	_
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	80	
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	320	mJ
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	I <sub>S</sub>	110 <sup>a, c</sup>	A
	T <sub>A</sub> = 25 °C	'S	2.6 <sup>b</sup>	^
Maximum Power Dissipation	T <sub>C</sub> = 25 °C		312ª	
	T <sub>C</sub> = 70 °C	PD	200	w
	T <sub>A</sub> = 25 °C		3.13 <sup>b</sup>	VV
	T <sub>A</sub> = 70 °C		2.0 <sup>b</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b</sup>	Steady State	R <sub>thJA</sub>	32	40	°C/W
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.33	0.4	0/11

Notes:

a. Based on  $T_C = 25$  °C.

b. Surface Mounted on 1" x 1" FR4 board.

c. Calculated based on maximum junction temperature. Package limitation current is 110 A.

Parameter	ess otherwis	Test Conditions	Min.	Typ.	Max.	Unit	
Static			1				
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	40			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			41			
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 8		mV/°(	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	2.0		4.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
		V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V			1		
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 V$ , $V_{GS}$ = 10 V	120			A	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		2			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 20 A		15		mΩ	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A		180		S	
Dynamic <sup>b</sup>	11		1	1	1		
Input Capacitance	C <sub>iss</sub>			9000			
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = 20 V, $V_{GS}$ = 0 V, f = 1 MHz		650		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			450		1	
Total Gate Charge	Qg			120			
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ = 20 V, $V_{GS}$ = 10 V, $I_{D}$ = 20 A		30		nC	
Gate-Drain Charge	Q <sub>gd</sub>			16			
Gate Resistance	Rg	f = 1 MHz		0.85	1.3	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			20	30		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, R <sub>L</sub> = 1.0 $\Omega$		11	17		
Turn-Off Delay Time	t <sub>d(off)</sub>			77	115	1	
Fall Time	t <sub>f</sub>			10	15	1	
Turn-On Delay Time	t <sub>d(on)</sub>			102	155	ns	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> = 20 V, R <sub>L</sub> = 1.0 Ω		62	95		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{\text{GEN}} = 4.5 \text{ V}, R_g = 1 \Omega$		180	270		
Fall Time	t <sub>f</sub>			60	90		
Drain-Source Body Diode Characteristic	s		1	1	1		
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			110	_	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				200	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 20 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			50	75	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L = 20 A di/dt = 100 A/ma T = 25 °C		70	105	nC	
Reverse Recovery Fall Time	ta	I <sub>F</sub> = 20 A, di/dt = 100 A/μs, T <sub>J</sub> = 25 °C		30			
Reverse Recovery Rise Time	t <sub>b</sub>			20		– ns	

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

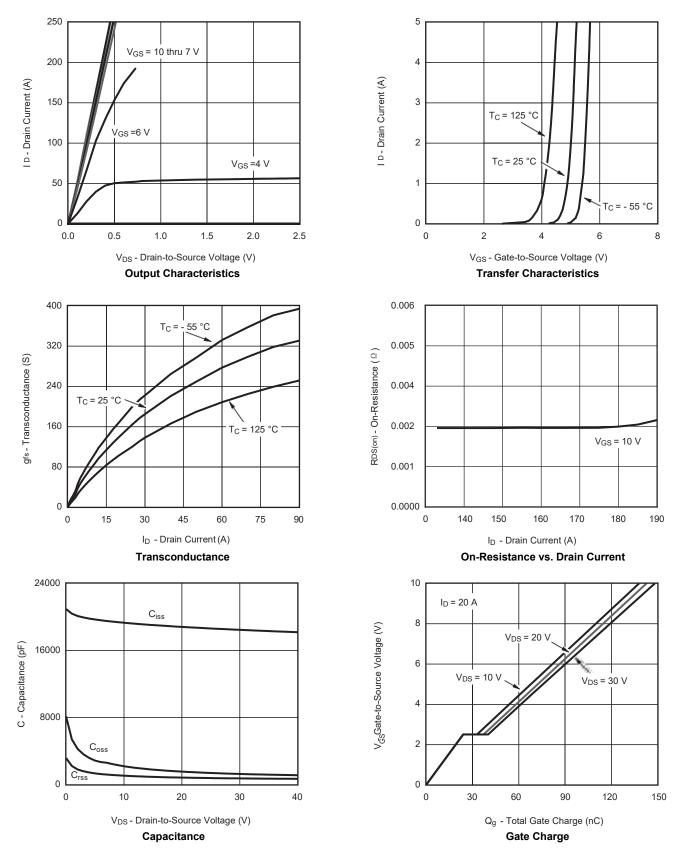
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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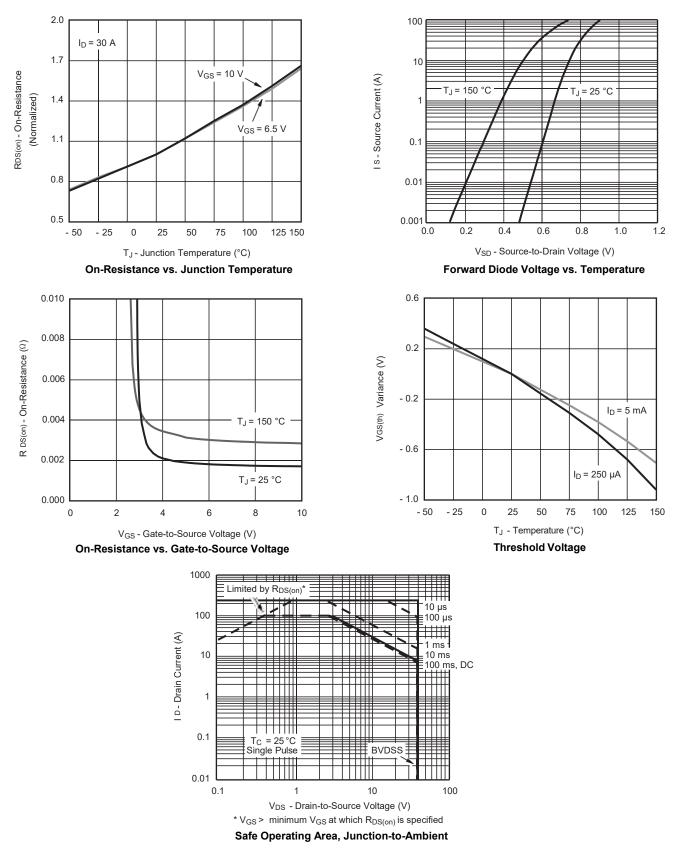


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

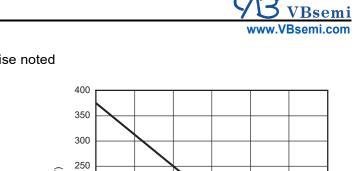




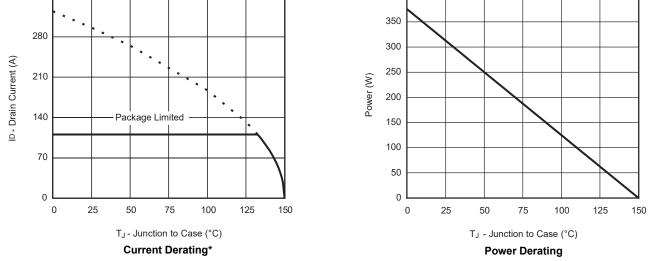
#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



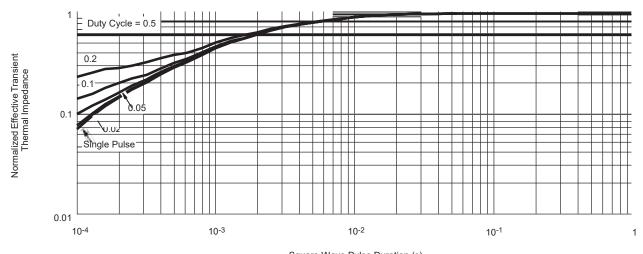
350



#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



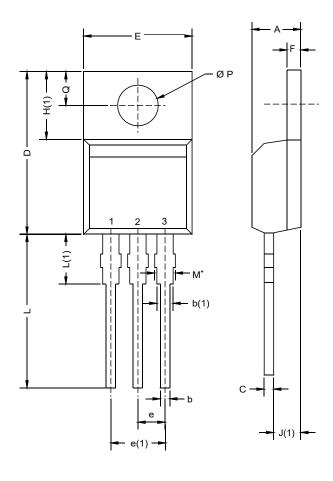
\* The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Square Wave Pulse Duration (s) Normalized Thermal Transient Impedance, Junction-to-Case



## **TO-220AB**



	MILLIM	ETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12			

#### Notes

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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